



Monolithic Galileo/GPS Front-End ASIC
8-March-2007



Contents

- Introduction to Chipidea
- Chip specifications
- Schematics overview
- Layout & Packaging
- Test Setup
- Characterization Tests
- Future – Receiver Tests
- Future – Radiation Tests
- Future – Next Spin

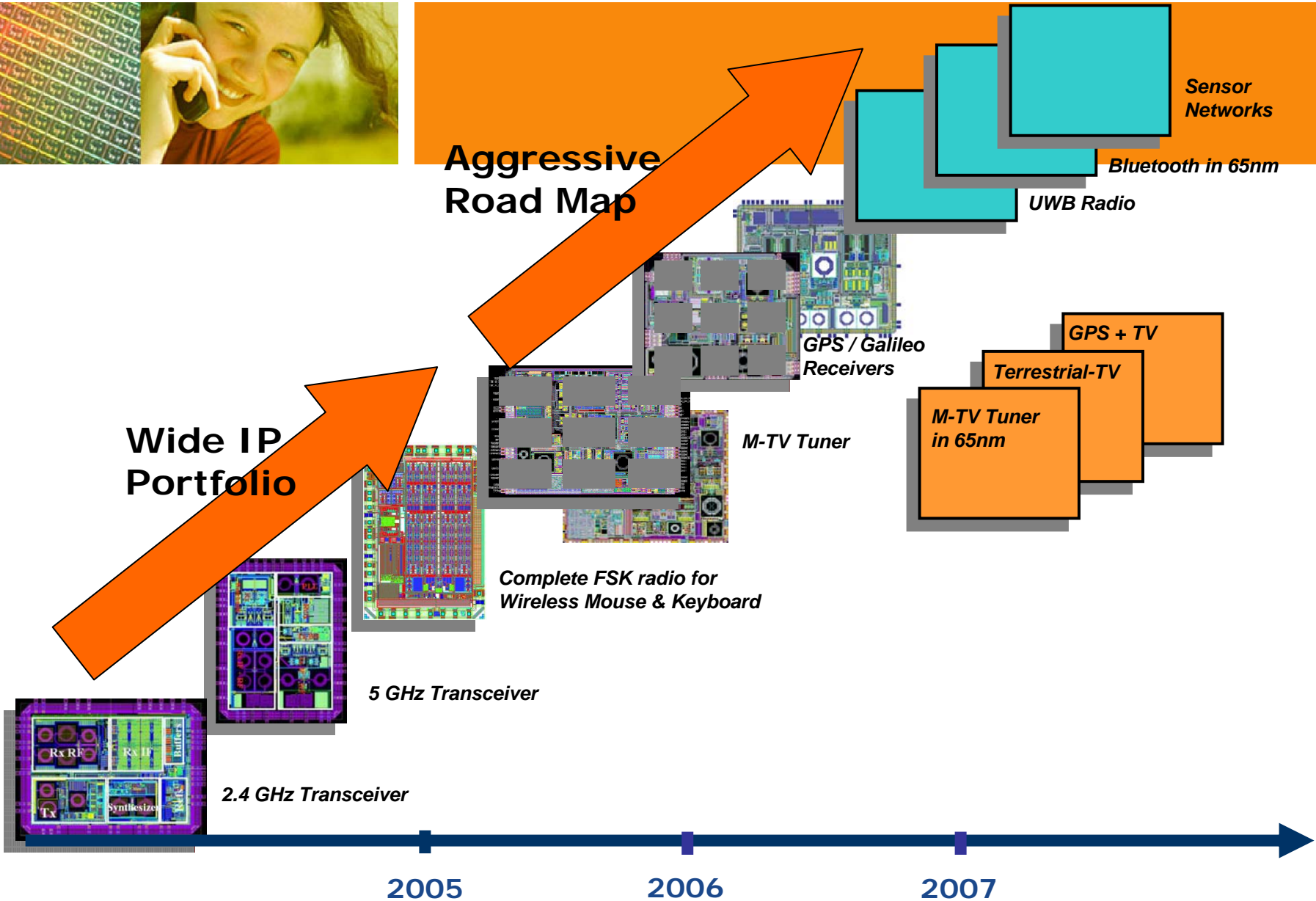


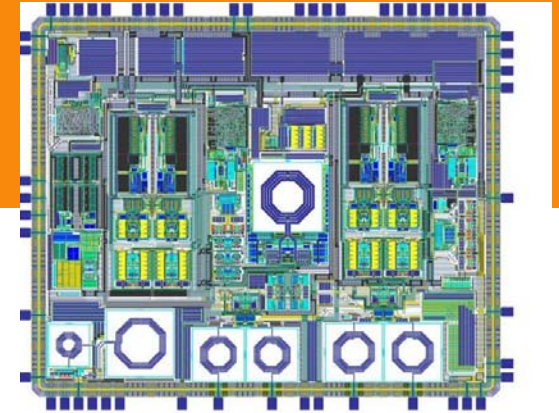
- **Complete system solution far beyond the RF chip**
 - Baseband converters that can be located either in the RF chip or Baseband SoC
 - Optimum partitioning of filters between analog and digital
 - Support functions such as supply regulation, clock generation, etc.
 - Advanced Digital Interfaces, such as 3GDigRF
- **Proven RF design competence**
 - From complete FSK radios for ISM HF bands to UWB RF front-ends
 - RF Transceivers in 2.4 GHz band and in 5 GHz band
 - For GPS receivers supporting Galileo
 - For Mobile TV covering all the bands (from VHF to L-Band) and standards (DVB-H, T-DMB, ISDB-T)
- **Working in close collaboration with Customers**
 - Incorporating exclusive differentiating features for better competitiveness
 - Adapting the interfaces to suit specific application



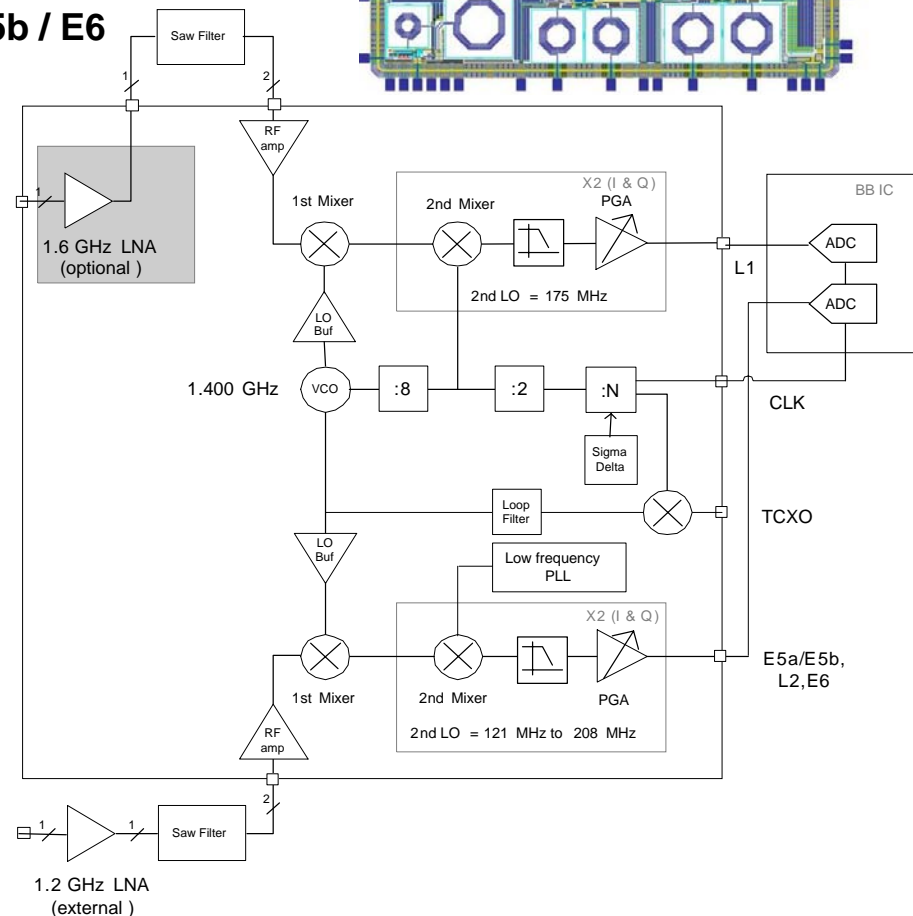
Aggressive Road Map

Wide IP Portfolio





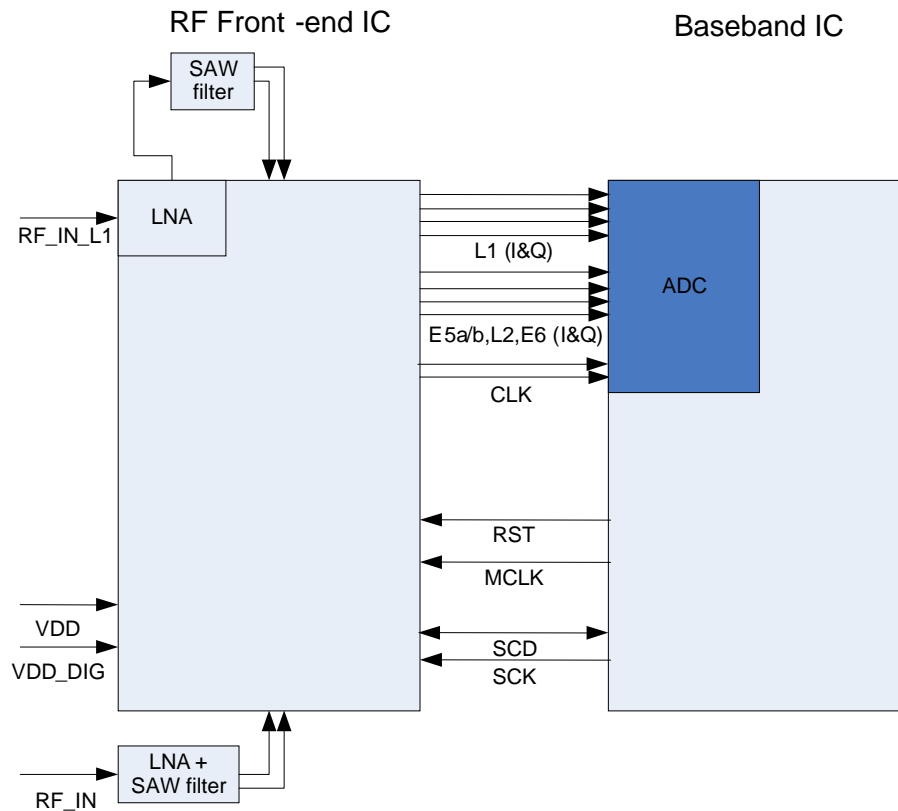
- **Targets Galileo & GPS Positioning Systems**
- **Multiple Band Reception E1 / L1 / L2 / E5a / E5b / E6**
- **Simultaneous reception of:**
 - L1 plus L2,
 - L1 plus E6,
 - L1 plus E5a or L1 or E5b,
 - L1 plus joint reception of E5a+E5b
- **Low BOM – “On-chip” Filtering with only external LNA and RF Filters**
- **Zero IF with DC cancellation and Automatic Gain Control**
- **Fully Integrated PLL**
- **Onboard Crystal Oscillator**
- **1.8 V Single Supply**
- **Current consumption: 25mA**
- **Chip Area: ~6.2 mm²**
- **First Silicon available**





Application Diagram

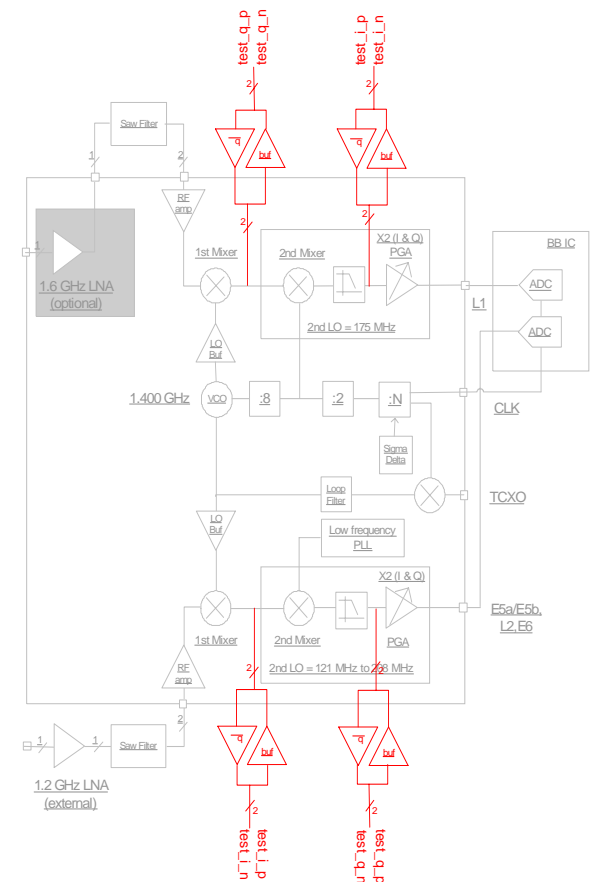
- Communication with baseband IC, control, configuration, testing





Testability

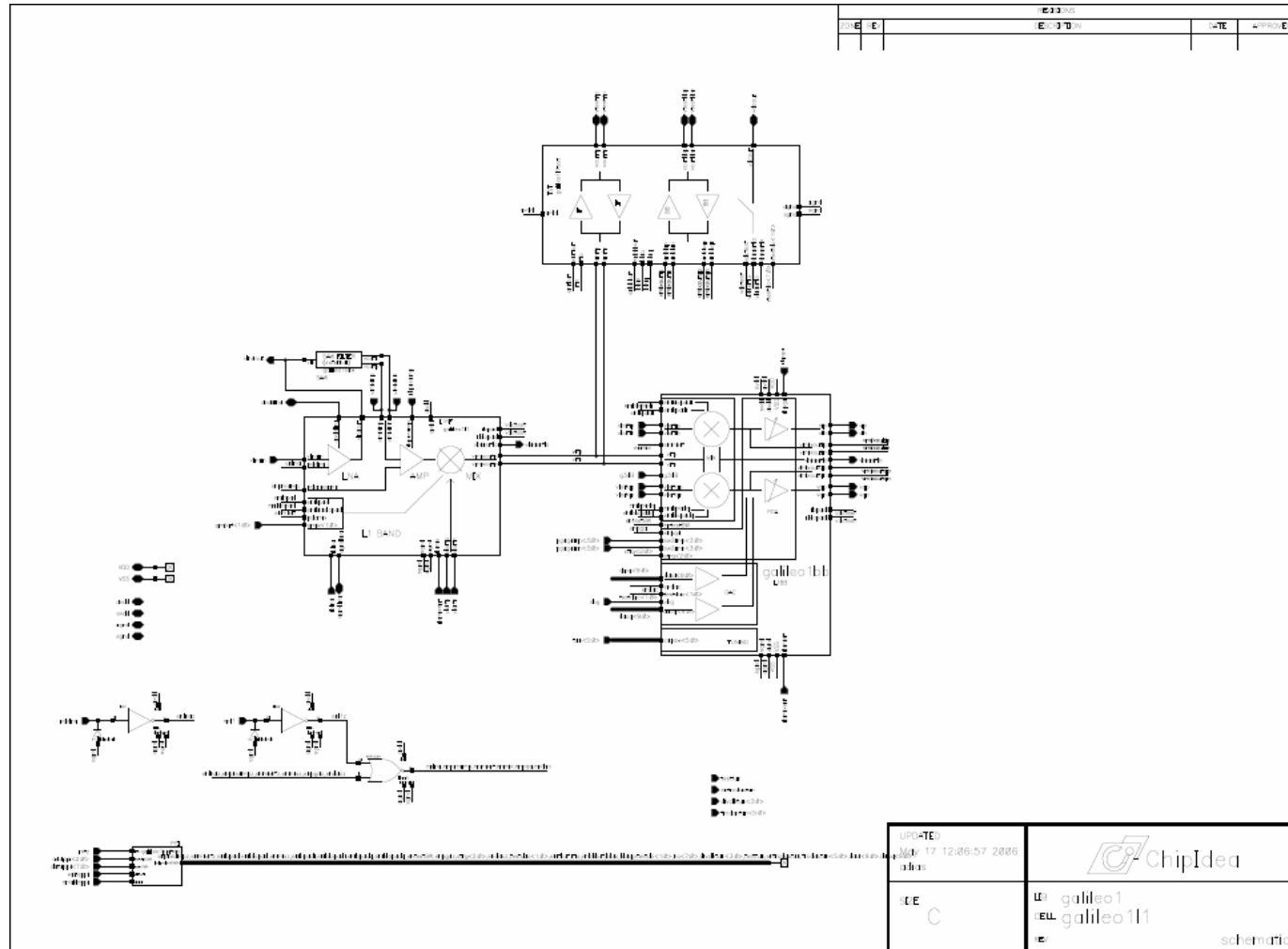
- Bi-directional buffers are strategically placed in critical node of the receiver.
- Four test pins are used for debug.
- The IF signal can be monitored or applied externally into the circuit for debug or characterization.
- The Baseband PGA input signal can be monitored or applied externally into the circuit for debug or characterization.
- Critical DC voltage of several blocks can be measured or forced using the four test pins.
- VDC_TEST: Dedicated test pin for Sigma Delta. Can output DC voltages of DUT, eg, Mixer CM, VCOs control Voltage, etc.





L1 receiver

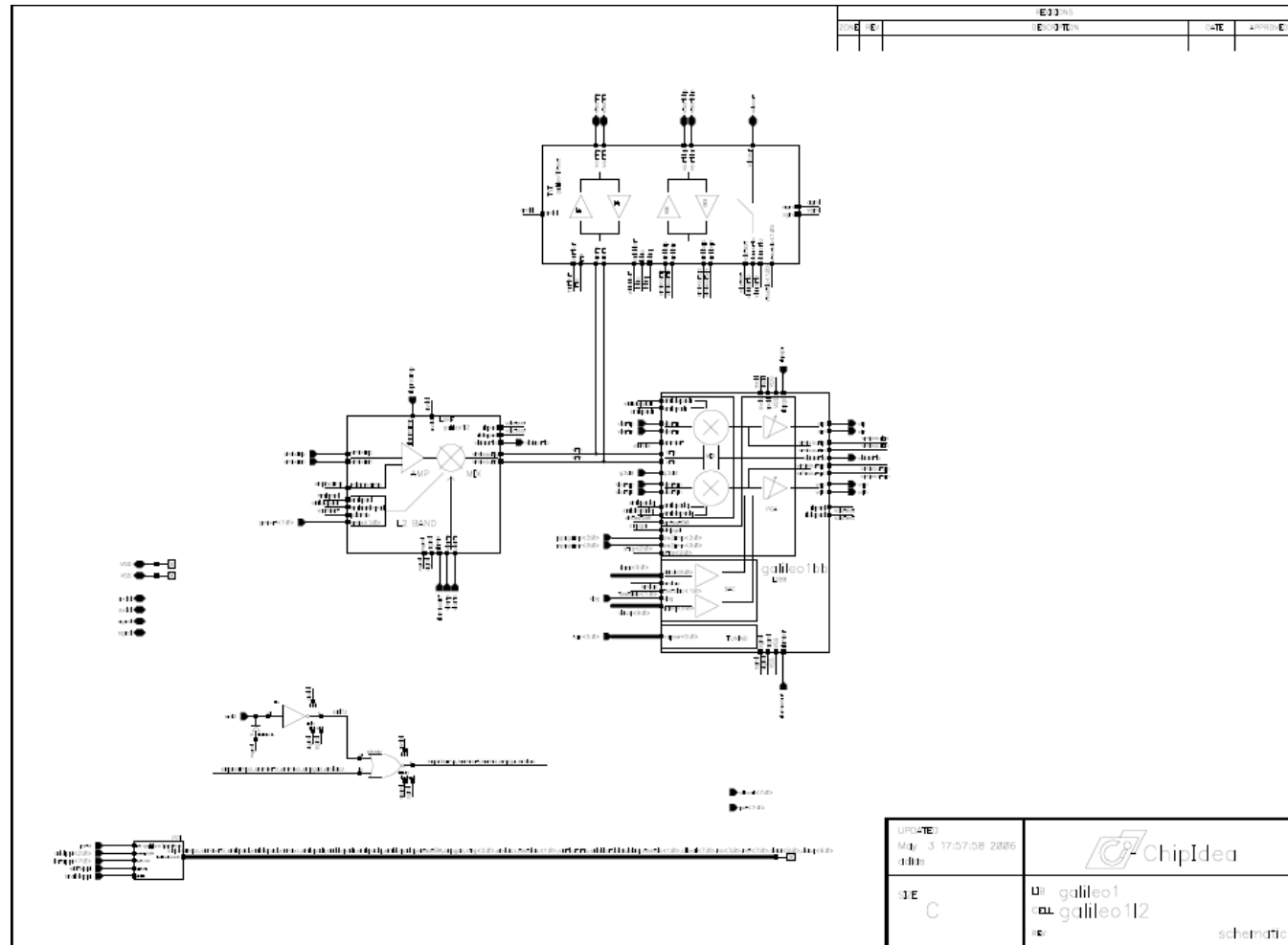
- LNA (opt)
- Preamp
- 1st mixer (175MHz)
- 2nd mixer (zero-IF)
- PGA
- IQ offset DACs





E5a/b L2 E6 receiver

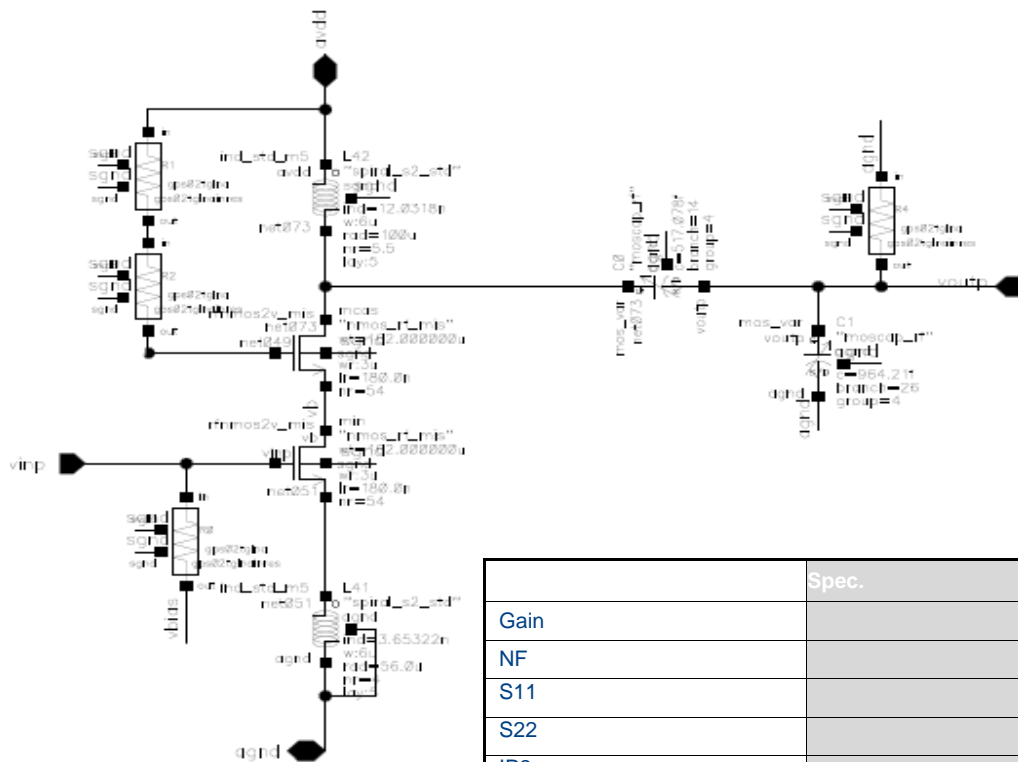
- Preamp
- 1st mixer
(121MHz to 208MHz)
- 2nd mixer
(zero-IF)
- PGA
- IQ offset DACs





LNA for GALILEO/GPS application

LNA for GALILEO/GPS application (1.6GHz)



- Single ended
- L degenerated architecture
- External Inductor

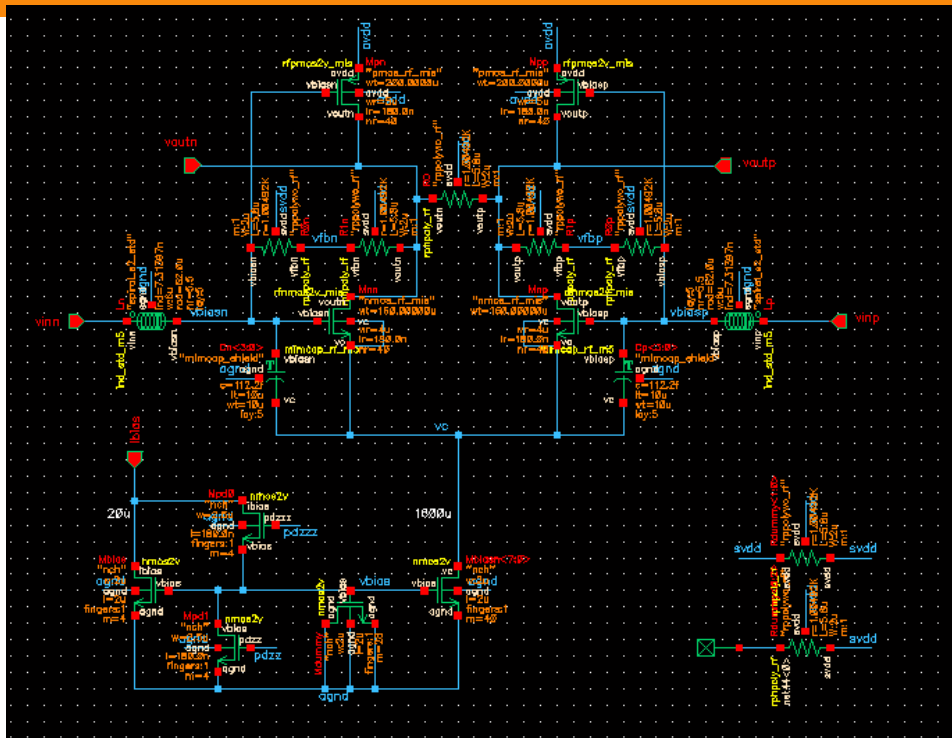
	Spec.				
Gain	15	13	15.6	17.8	dB
NF	< 2 max	1.1	1.3	1.6	dB
S11	< -10 min	-16.7	-13.4	-10.9	dB
S22	< -10 min	-23.5	-15.9	-12.3	dB
IP3	> 0	-	1.2	-	dBm



RF Preamp L1

RF Preamp L1 (1.6GHz)

- Differential input
- Requires no external components



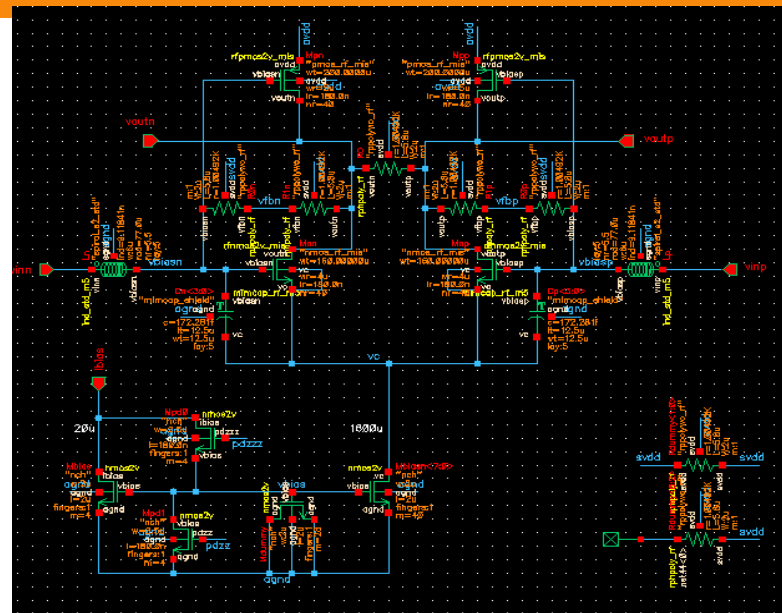
		Spec.				
G1575	Gain for 1575MHz frequency	> 12	12.94	14.97	16.86	dB
NF1575	Noise figure for 1575MHz frequency	< 5	1.86	2.59	3.44	dB
S11_1575	Input matching coefficient for 1575MHz frequency	< -12	-16.89	-25.3	-39.89	dB
IIP3	Input referred 3 rd order interception point	> -20	0.85	2.51	3.93	dBm



RF Preamp L2/E5/E6

RF Preamp L2/E5/E6

- Differential input
- Requires no external components
- Designed form 1.1GHz to 1.3GHz



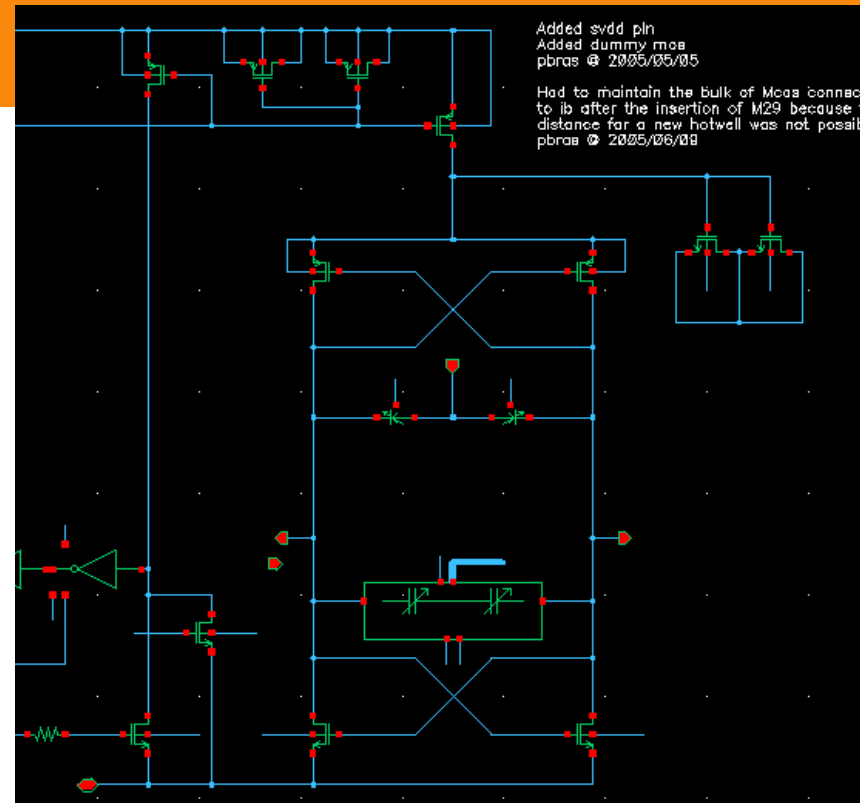
		Spec.				
G1150	Gain for 1150MHz frequency	> 14	14.12	16.82	19.42	dB
G1300	Gain for 1300MHz frequency	> 14	14.06	16.33	18.39	dB
NF1150	Noise figure for 1150MHz frequency	< 4	1.91	2.67	3.56	dB
NF1130	Noise figure for 1300MHz frequency	< 4	1.87	2.63	3.58	dB
S11_1150	Input matching coefficient for 1150MHz frequency	< -9	-27.45	-16.36	-10.97	dB
S11_1130	Input matching coefficient for 1300MHz frequency	< -9	-48.53	-25.12	-16.8	dB
IIP3	Input referred 3 rd order interception point	> -30	0.257	1.91	3.34	dBm



1.4GHz VCO

1.4GHz VCO

- Programmable capacitors to increase tuning range
- Integrated LC
- Low Phase noise



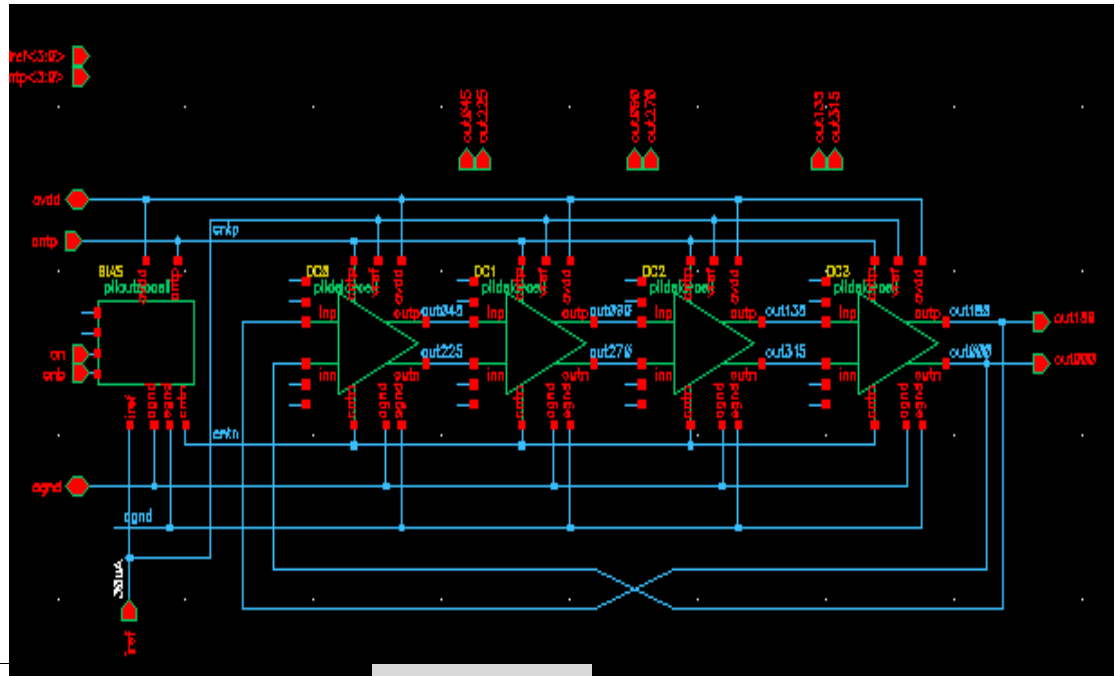
		Spec.				
VCO_Idc	VCO current consumption	>-2.5e-3	-2.25e-3	-2.11e-3	-1.99e-3	A
VCO_Vpk	VCO output amplitude peak	>0.7	660e-3	877e-3	1.173	V
VCO_dF	VCO gain dF/dV	>50	33.33	373.3	201.8	MHz/V
PhaseNoise	VCO phase noise @ 1K	<-70	-57.55	-55.83	-45.03	dBc/Hz
PhaseNoise	VCO phase noise @ 10K	<-70	-84.96	-83.82	-73.56	dBc/Hz
PhaseNoise	VCO phase noise @ 100K	<-75	-108.1	-108	-100.9	dBc/Hz
PhaseNoise	VCO phase noise @ 1M	<-95	-129	-129	-124.1	dBc/Hz
PhaseNoise	VCO phase noise @ 5M	<-108	-141.3	-141.3	-136.4	dBc/Hz



120MHz-225MHz VCO

120MHz-225MHz

- Four stages ring oscillator
- I & Q phases available

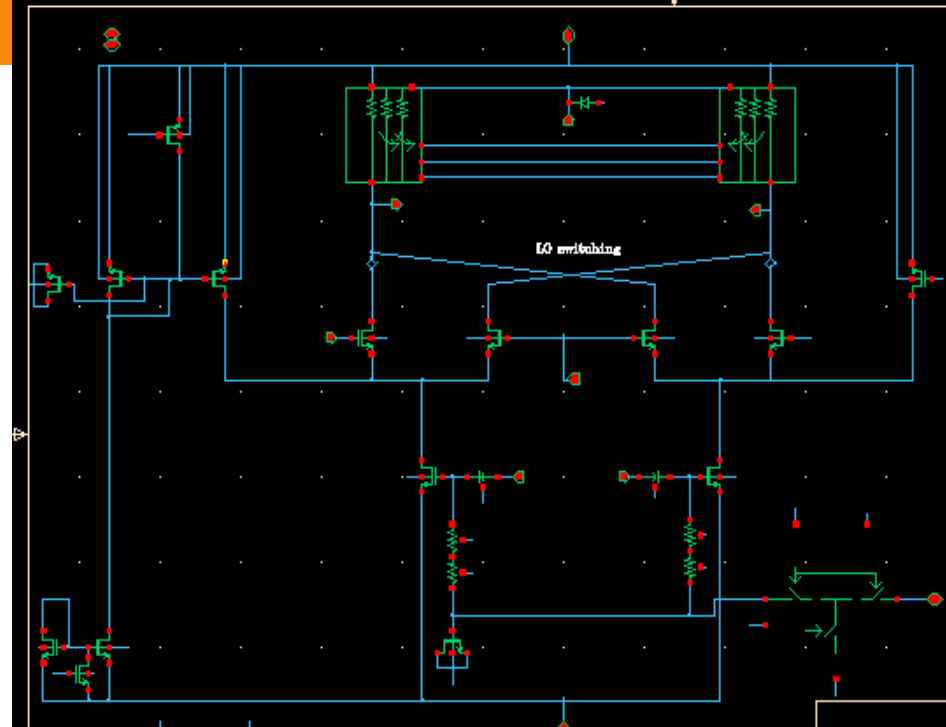


		Spec.				
irmsavdd	VCO consumption	<0.0015	286e-6	306e-6	1.54e-3	A
voutdiff	VCO output amplitude	>0.6	645e-3	829e-3	1.223	Vpp
Kvco	VCO sensitivity	<100e6	-1.27e6	22.9e6	235e6	Hz
PhaseNoise	VCO phase noise @ 100KHz	<-75	-91.12	-88.21	-84.01	dBc/Hz
PhaseNoise	VCO phase noise @ 1MHz	<-95	-112.8	-110	-105.6	dBc/Hz
PhaseNoise	VCO phase noise @ 5MHz	<-108	-129.1	-126.3	-121.8	dBc/Hz
loff	Current consumption power down	>0.1e-6	-687.80e-9	-9.36e-9	-1.67e-9	A



1st Mixer

1st Mixer



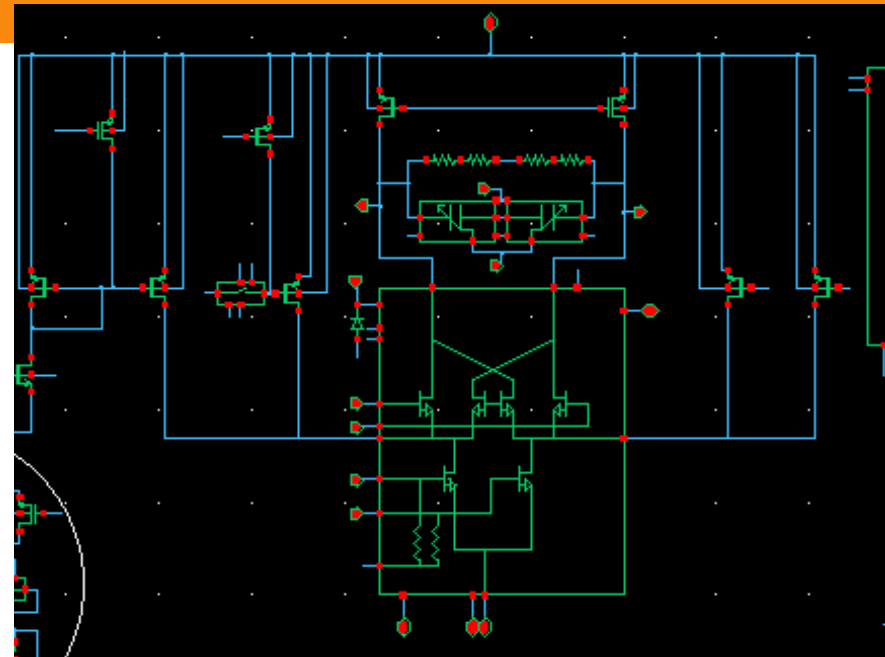
		Spec.				
Gc	Conversion Gain	13	8.39	13	17.79	dB
NF	Noise Figure- DSB	18	15.8	17.9	20.1	dB
IIP3	Input 3 rd order interception point	-18	-2.76	-0.85	-4.52	dBm
IIP2	Input 2 nd order interception point	-	-	-30	-	dBm
lavddon	Current drawn from avdd in normal operation mode	1.5	1.45	1.51	1.59	mA
lavddpd	Current drawn from avdd in power-down mode	-	0.1	0.19	0.44	uA



2nd Mixer

2nd Mixer

- Gilbert Cell
- I & Q for image rejection
- Integrated Filter

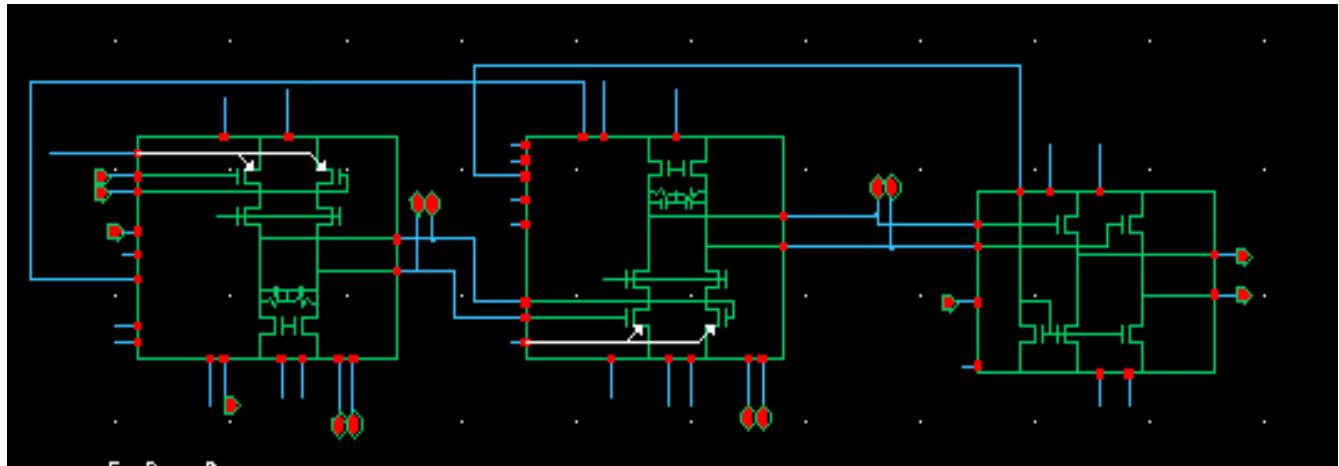


		Spec.				
Gc	Conversion Gain	21.5	16.03	19.5	22.86	dB
NF	Noise Figure- DSB	19.5	16.95	18.92	20.71	dB
IIP3	Input 3 rd order interception point	-4	-10	-2.97	3.3	dBm
IIP2	Input 2 nd order interception point	-		-40		dBm
lavddon	Current drawn from avdd in normal operation mode	1.5	0.82	0.85	0.89	mA
lavddpd	Current drawn from avdd in power-down mode	-	0.06	0.14	0.37	uA



PGA

PGA



		Spec.				
Gmin	minimum Voltage Gain	3	-4.66	2.74	11.20	dB
Gmax	maximum Voltage Gain	51	42.70	49.80	57.30	dB
Gstep	Gain Step	=6		6		dB
NF	Noise Figure @ 10MHz (Max. Gain)	<40	20.08	20.85	21.53	dB
IIM3	IIM3 with maximum gain to allow no distortion at output	TBD	-	-61.73	-	dBV
Iavddon	Current drawn from avdd in normal operation mode (w/out Buffer)	< 1	-	0.52	-	mA



Layout



1. Die

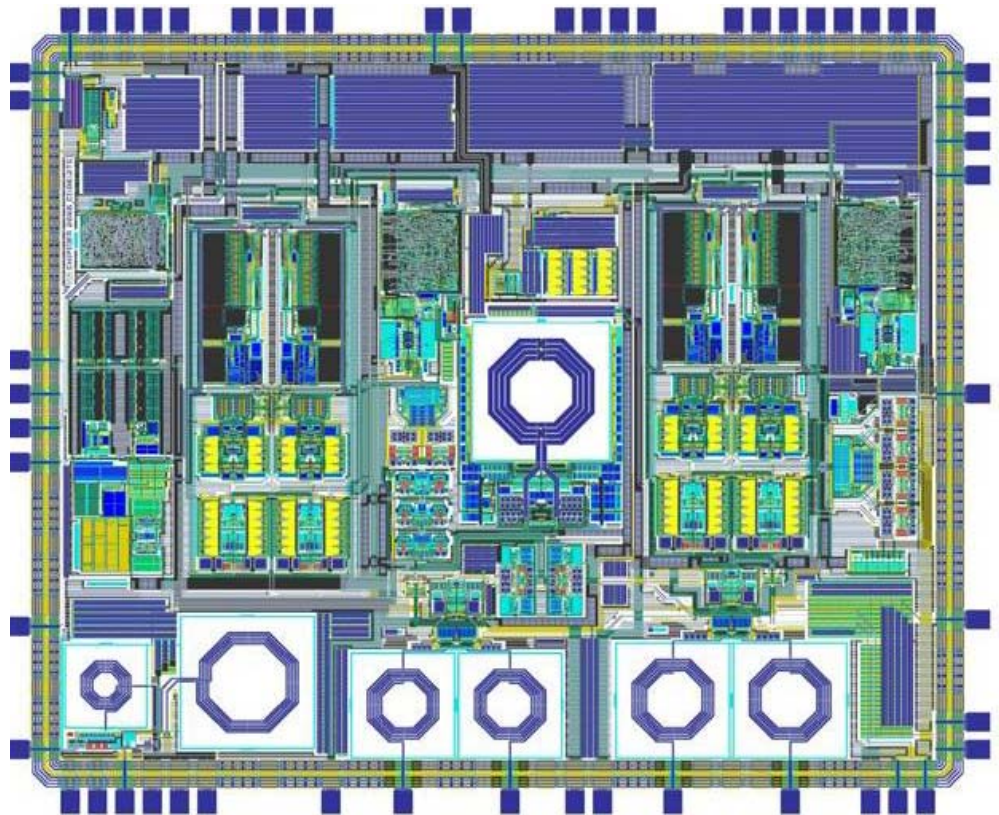
Dimensions in millimeters

Die external dimensions: l , w , t	3000 x 2500x 0.9
Minimum Bond Pad opening area: l , w	63 x 66 [um]
Minimum Bond Pad pitch	80 [um]

2. Package

Dimensions in millimeters

Type	QFN
Number of Pins	32
Pin Pitch	0.5mm
Body: l , w	5mm x 5mm
Body Material	Plastic, RoHS Compliant





Test Overview

- **Test Development**
- **Test Setup Review**
- **Characterization Tests**
 - Power Consumption
 - LNA
 - L1, L2 Complete Chain
 - Phase Noise
 - Sigma-Delta Spurs
 - LPF
 - Channel Isolation
 - IQ Mismatch
- **Summary**



Test Development

Packaging

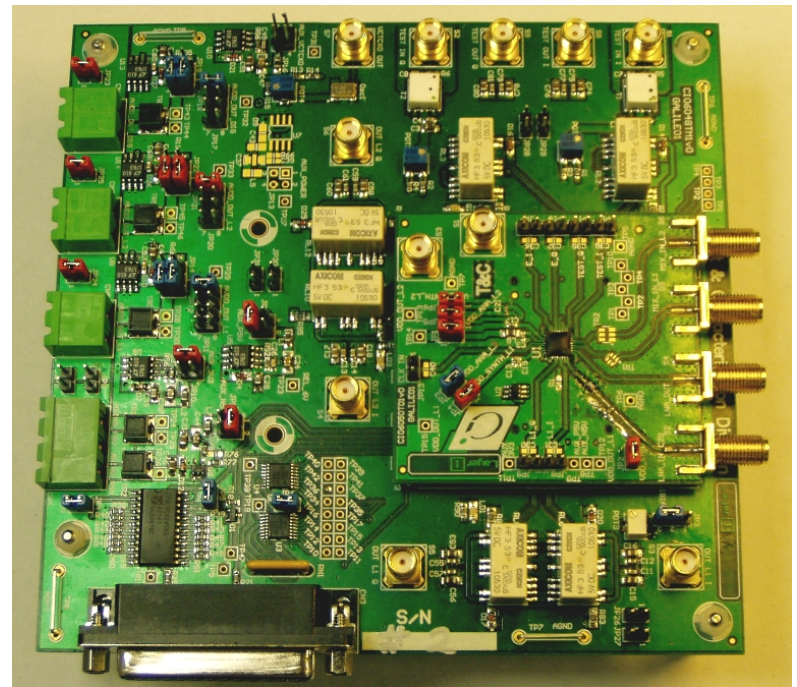
- QFN32 for high RF performance

Hardware

- MotherBoard
- DaughterBoards
- De-embedding Boards
(SAW Filter, Balun, PCB traces)

Software

- Flexible software Control (I2C)



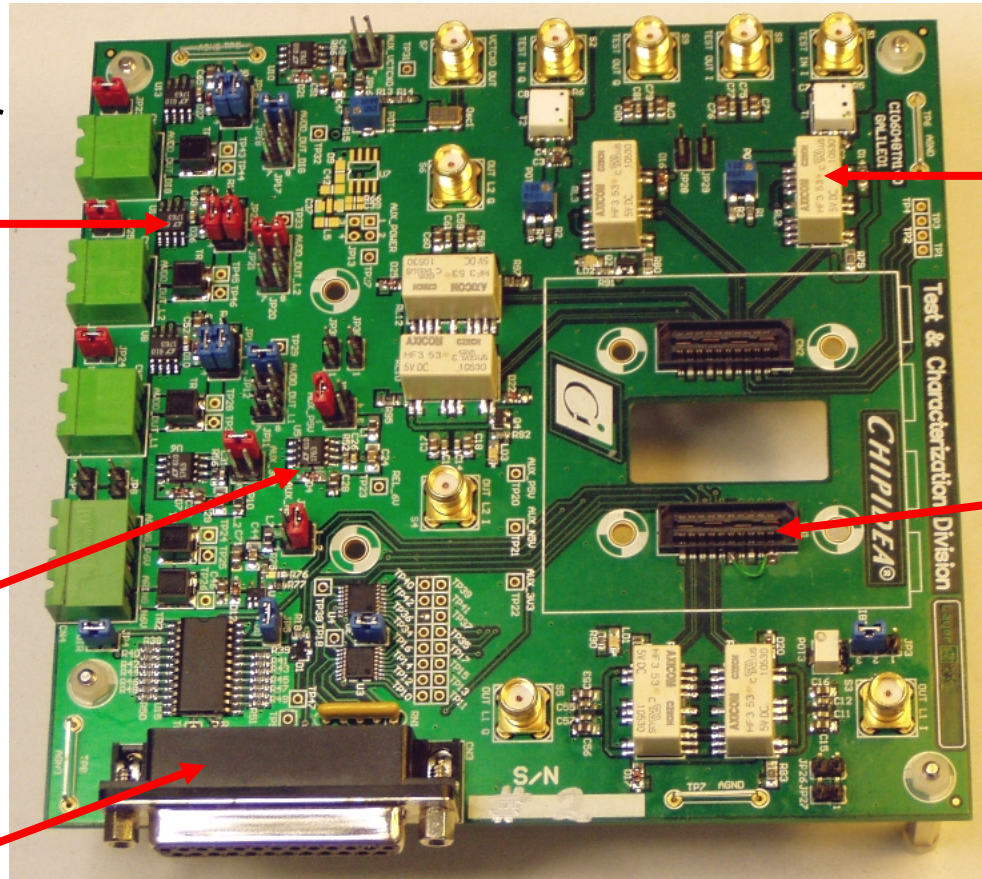


Motherboard

Programmable power supplies and DUT biasing

Buffers for base-band Interface

I2C – PC communication



Relays for signal switching

DB Interface

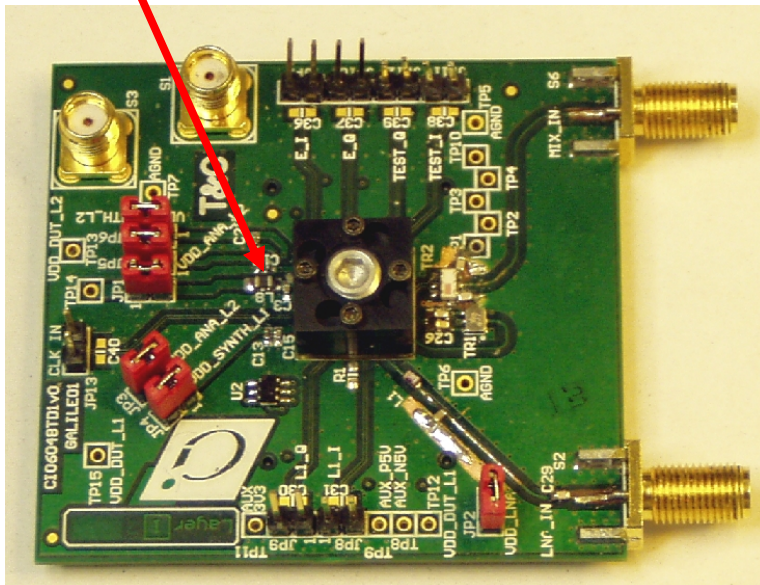


Daughterboards

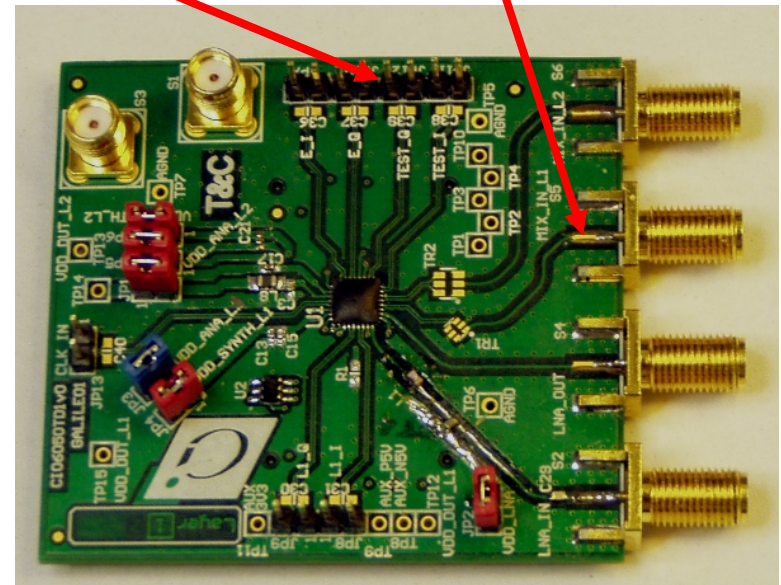
Two Types:

- Type I: with RF QFN socket and SAW filter
- Type II: for direct DUT soldering and LNA characterization

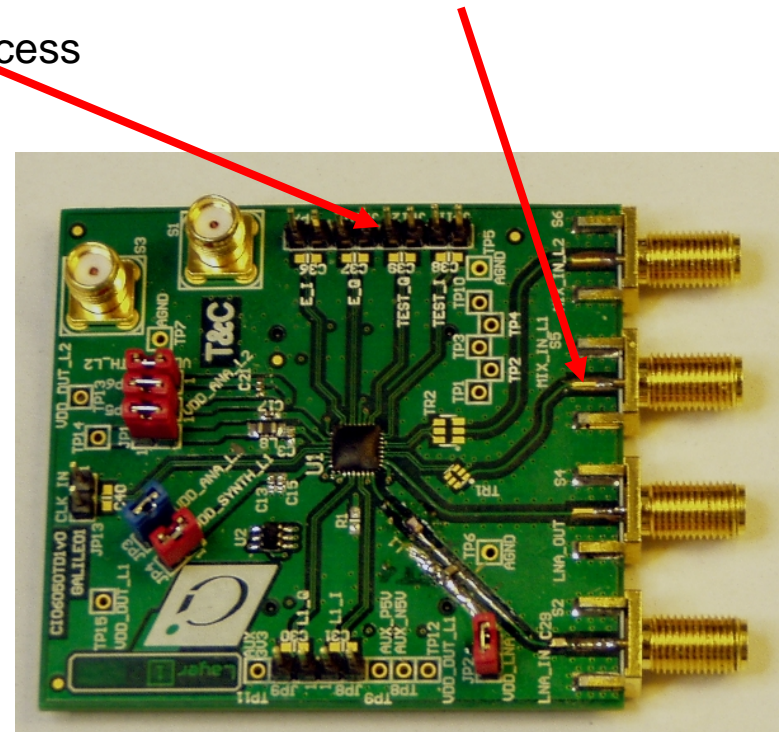
Power supply decoupling



Test buffers access



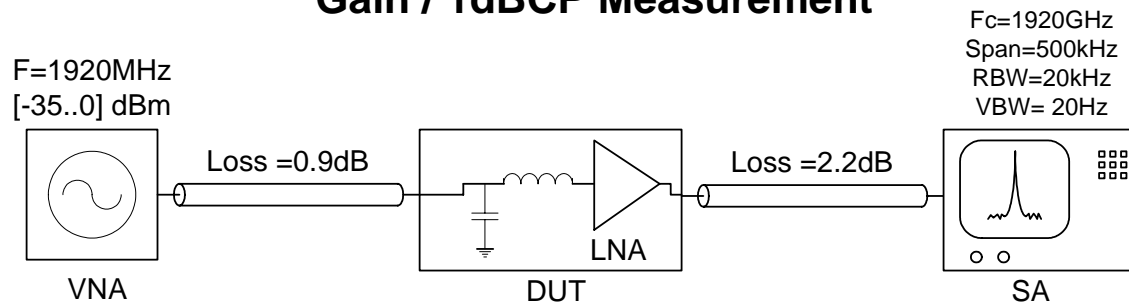
RF signal routing



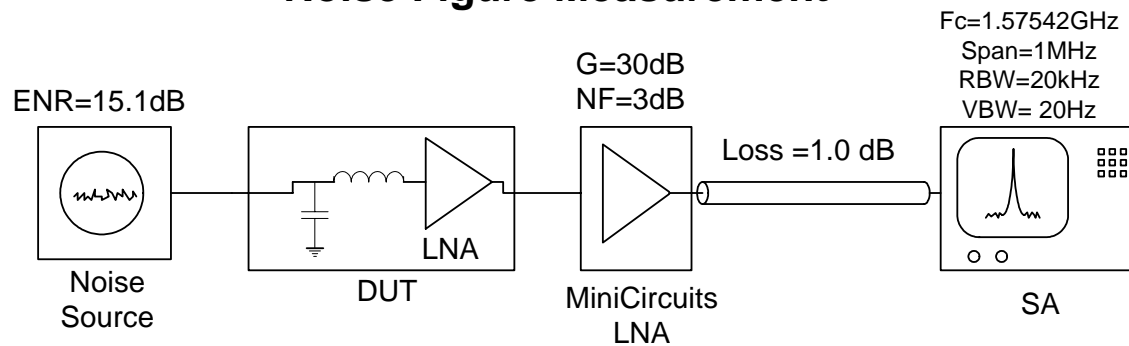


Test Setup: NF, 1dBCP

Gain / 1dBCP Measurement



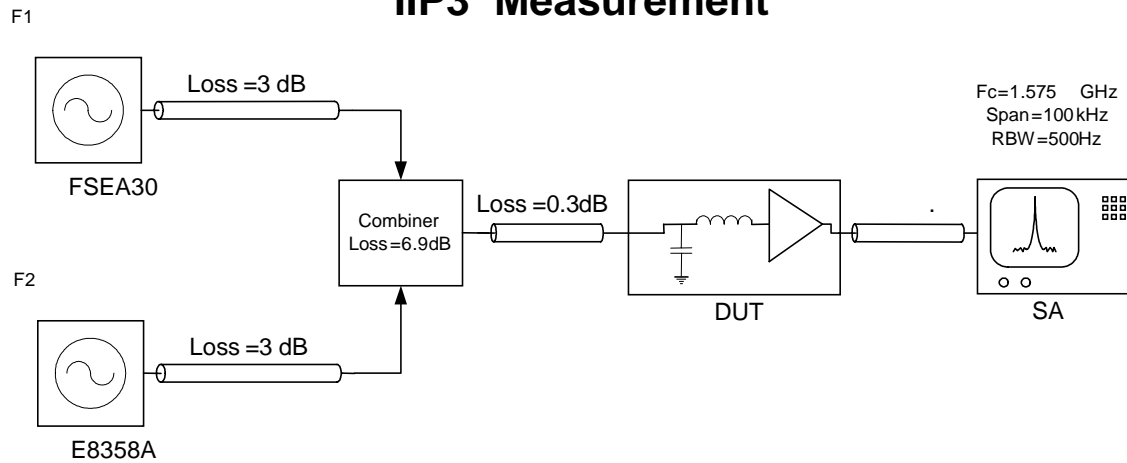
Noise Figure Measurement



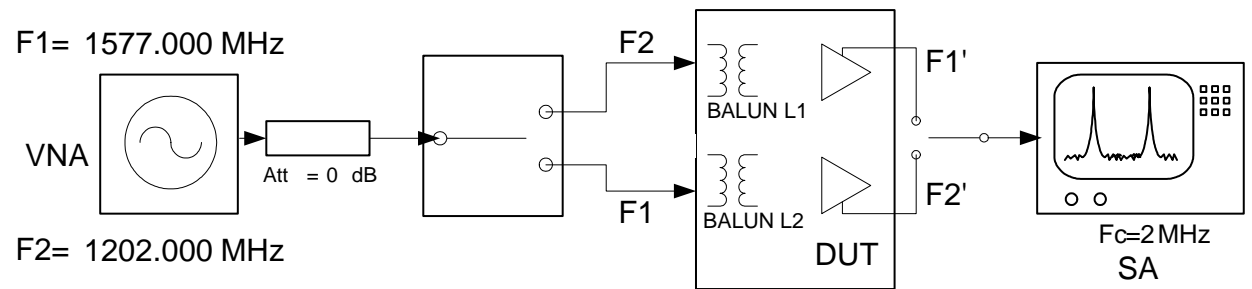


Test Setup: IIP3

IIP3 Measurement



Isolation between channels



$F1' = F1$ down converted to Bbi,q

$F2' = F2$ down converted to Bbi,q



Test – Power Consumption

Setup:

- Using standard lab Power Supplies and intercepting individual power domains of DUT

FIB # 3 / 1.8V		PGAs set to G=12dB			
POWER CONSUMPTION (mA)			Powerdown		
Domain	Measured	MAX. Spec	Domain	Measured	
VDD_LNA	3.42	4	VDD_LNA	14 nA	
VDD_ANA_L1	14.57	23	VDD_ANA_L1	120 nA	
VDD_SINTH_L1	0.515	1.5	VDD_SINTH_L1	22 nA	
VDD_ANA_L2	9.84	16	VDD_ANA_L2	10 nA	
VDD_SINTH_L2	0.427	1.5	VDD_SINTH_L2	1 nA	
VDD_DIGITAL	2.54	4	VDD_DIGITAL	240 nA	
TOTAL	31.312	50	TOTAL	<400 nA	

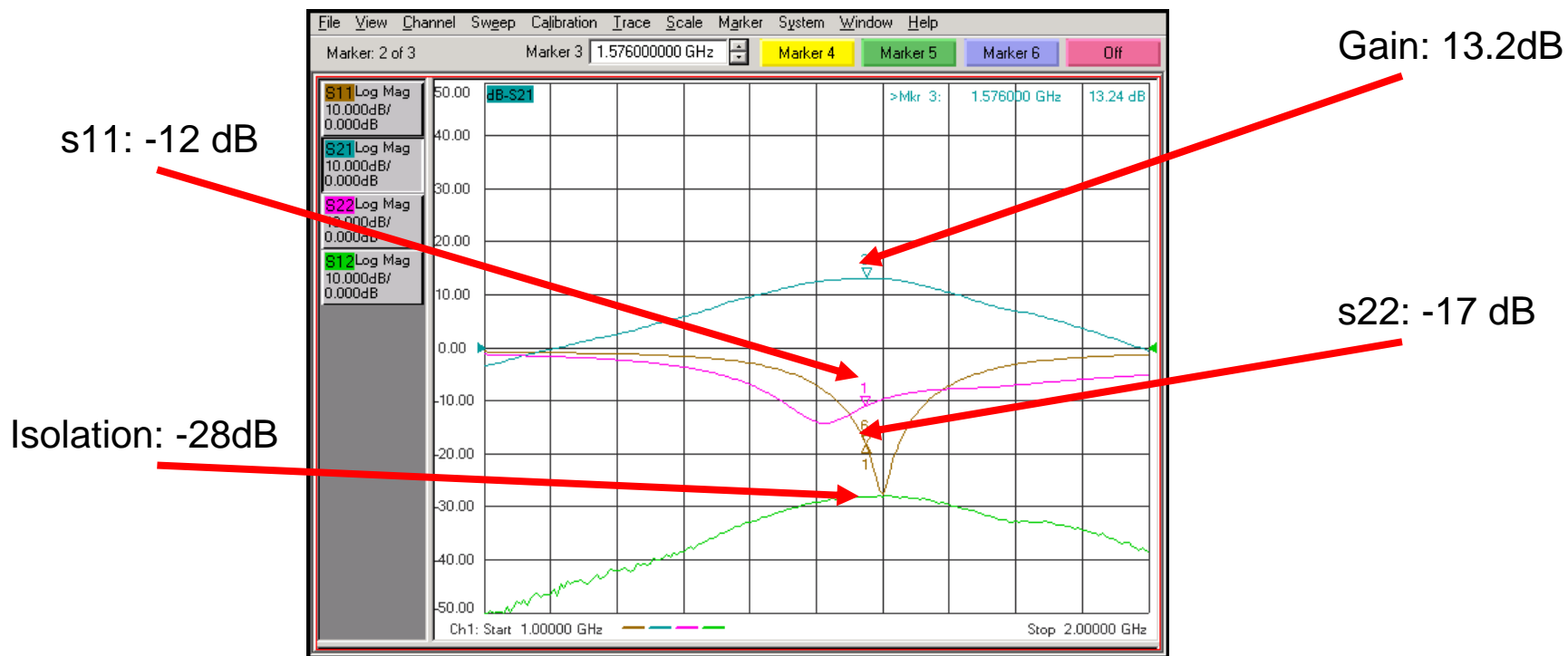




LNA – s-Parameters

Setup:

- Calibrated VNA, after LNA input impedance matched (5.6nH Series, 3p3 Shunt)

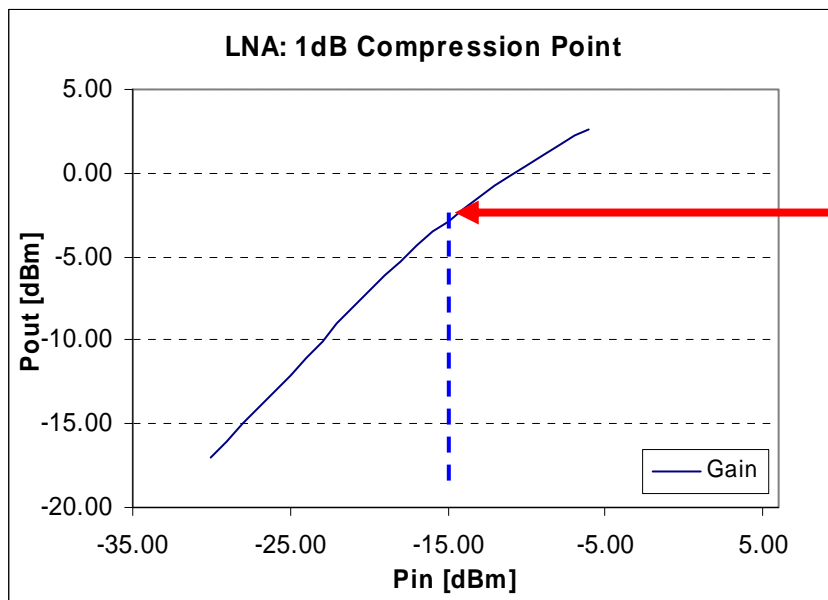




LNA – Linearity and Noise

Setup:

- LNA input impedance matched (5.6nH Series, 3p3 Shunt)



→ NF=2.5dB (typ)

1dBBCP: -15dBm

LNA: IIP3	
Condition	IIP3 (dBm)
Out of Band (f1=1.675GHz, f2=1.775GHz)	4
	5.5
In Band (f1=1.575GHz, f2=1.576GHz)	1.4
	1.4



L1, L2 RF_AMP Input Impedance





L1 - Complete Chain (RF_AMP to PGA)

Setup:

- $G(\text{RF_AMP}) = 15\text{dB}$
- $G(\text{RF_MIXER}) = 4\text{dB}$
- $G(\text{IF_MIXER}) = 20\text{dB}$
- $G(\text{PGA-p, PGA-n}): (24,0)$ or $(0,24)\text{dB}$
- $\text{SD}=0$

Results:

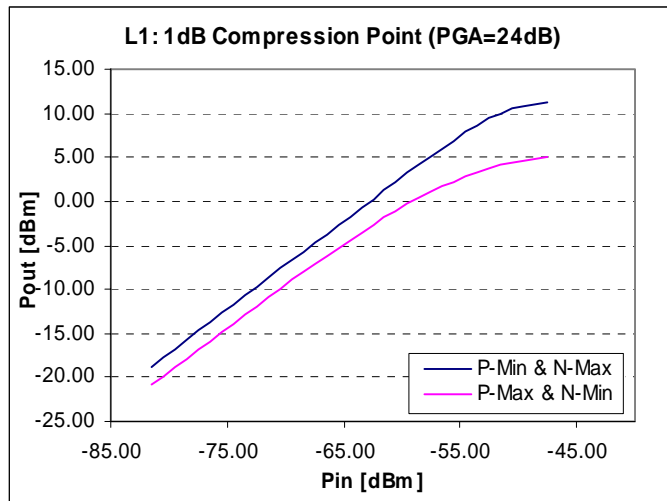
- ✓ Gain = 52 dB, step OK!
 - ✓ $1\text{dBCP} = -52.5\text{dBm}$
 - ✓ $\text{IIP3} = -18.3\text{dBm}$ ←
- (-35dBm referred to LNA input, spec=-40dBm)
- ✗ $\text{NF} = 6.5\text{dB}$ (spec: 5.35dB)

IIP3 Setup:

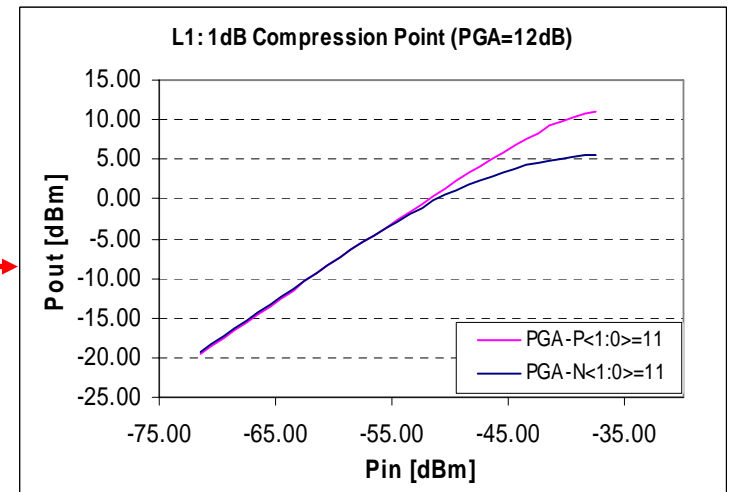
- $f_1=1.69\text{ GHz}$, $f_2=1.81\text{ GHz}$
- $\text{Pin}=-37.5\text{ dBm}$
- $\text{PGA-p}=12\text{dB}$



L1 – Complete chain



GPGA reduced to 12dB

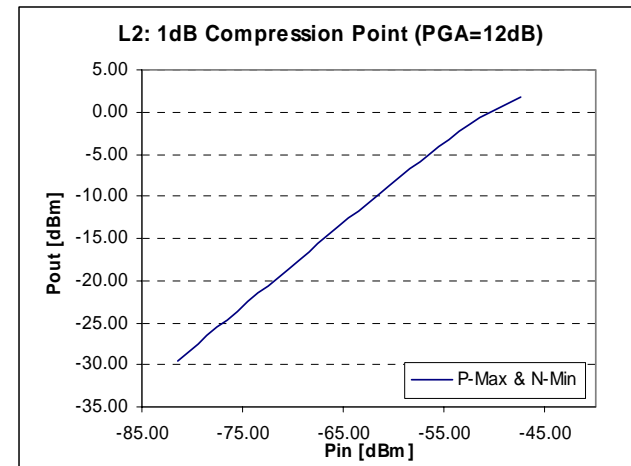




L2 - Complete Chain

Setup:

- $G(\text{RF_AMP}) = 15\text{dB}$
- $G(\text{RF_MIXER}) = 4\text{dB}$
- $G(\text{IF_MIXER}) = 20\text{dB}$
- $G(\text{PGA-p, PGA-n}): (24,0)$ or $(0,24)\text{dB}$
- $\text{SD}=0$



Results:

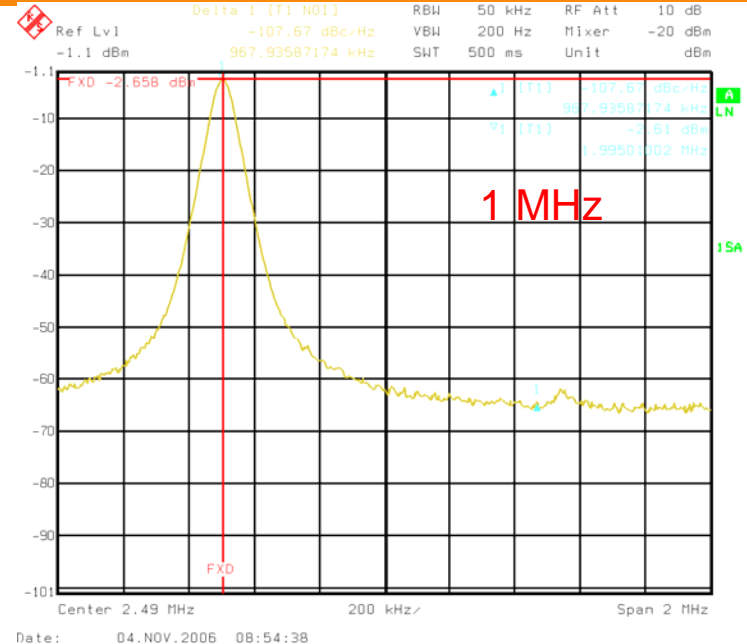
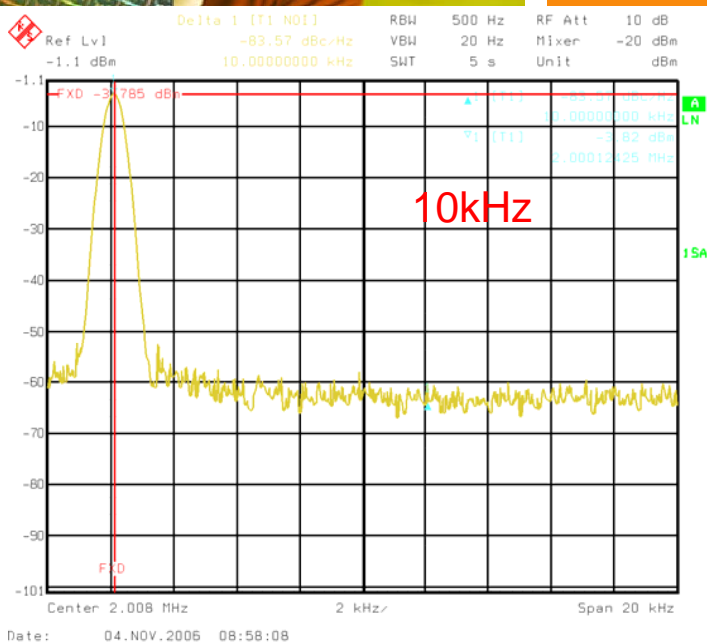
- ✓ Gain = 51.8 dB (should be 51dB), step OK!
- ✓ 1dBBCP= -52.5dBm
- ✓ IIP3 = -19.6dBm ←
- ✗ NF = 7.5dB (spec: 5.35dB)

IIP3 Setup:

- $f1=1.31$ GHz, $f2=1.43$ GHz
- $\text{Pin}=-50.0$ dBm
- $\text{PGA-p}=12\text{dB}$



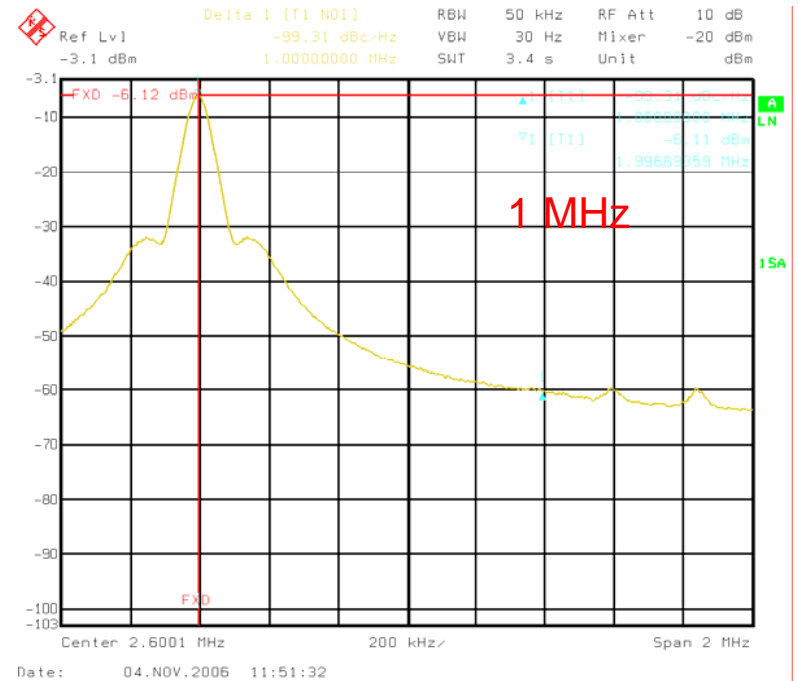
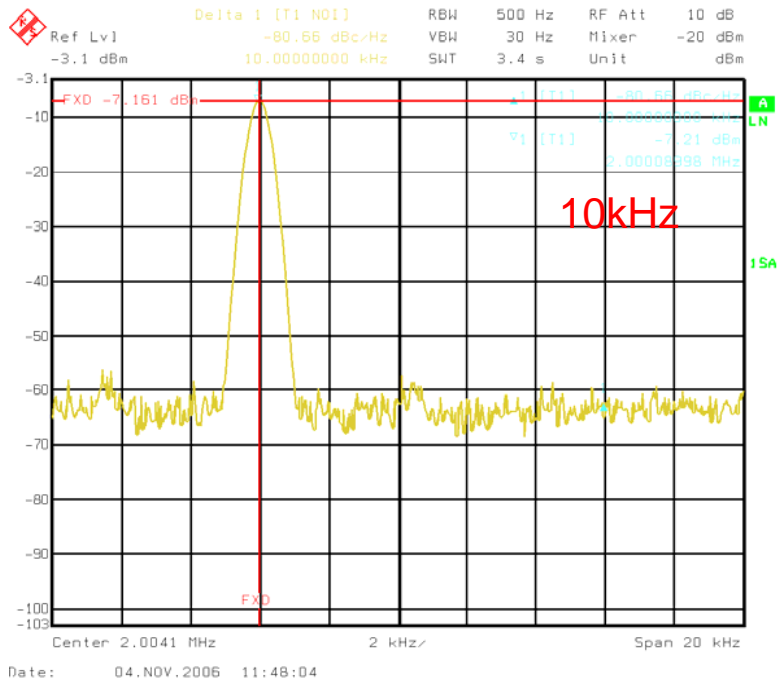
L1 – Phase Noise at Base-band (SD=0)



L1 – COMPLETE CHAIN					
Pin @ RF-AMP [dBm]	PGA GAIN	OFFSET	PHASE-NOISE [dBc/Hz]	SPECIFICATION	
-51.5	0dB	1 kHz	-77.6	na	
-51.5	0dB	10 kHz	-83.2	-70	
-51.5	0dB	57 kHz	-75	na	
-51.5	0dB	100 kHz	-84.4	-75	
-51.5	0dB	1MHz	-107.3	-95	



L2 – Phase Noise at Base-band (SD=0)

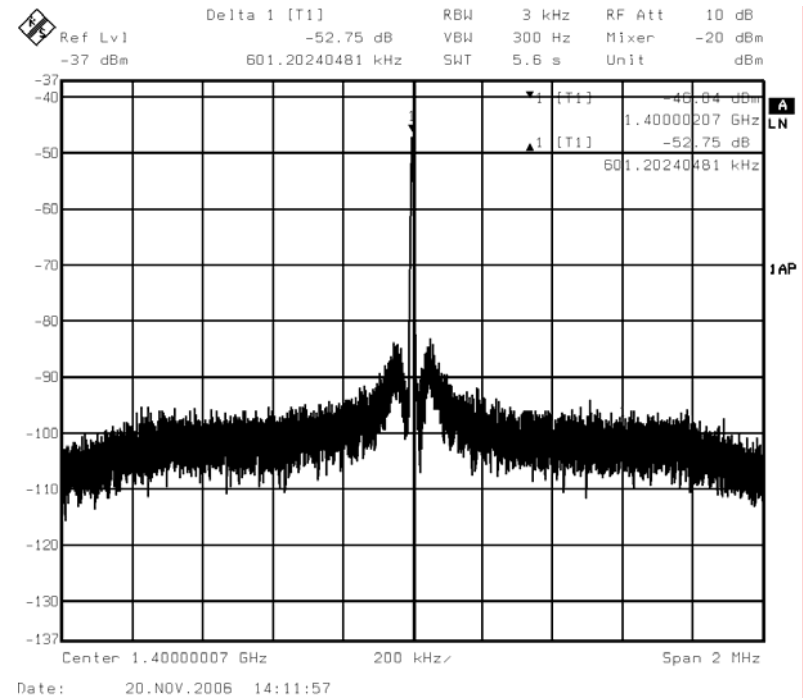
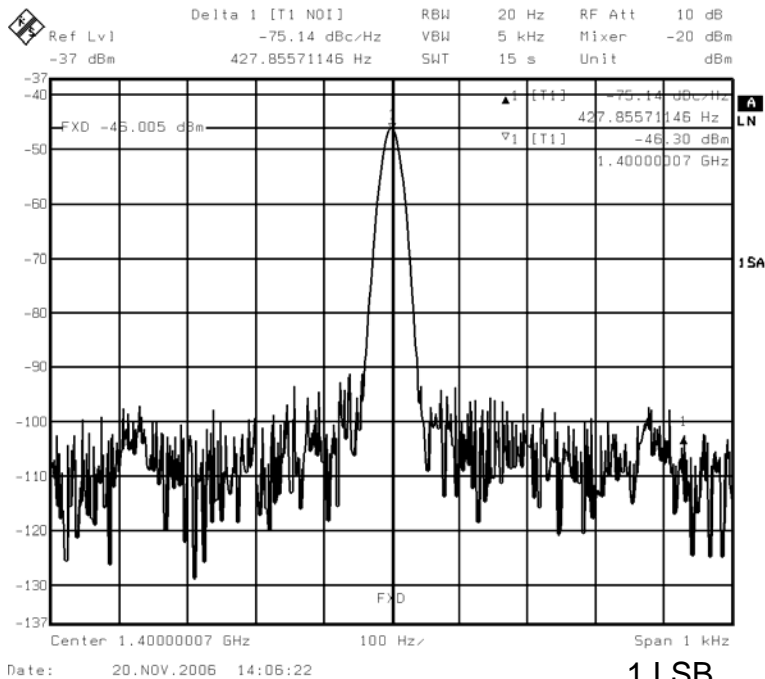


L2: COMPLETE CHAIN				
Pin @ RF-AMP [dBm]	PGA GAIN	OFFSET	PHASE-NOISE [dBc/Hz]	SPECIFICATION
-54	24dB	1KHz	-79.5	na
-54	24dB	10KHz	-81.5	-70
-54	24dB	100KHz	-81	-75
-54	24dB	1MHz	-98.4	-95



SIGMA-DELTA Spurs L2 (Both PLLs)

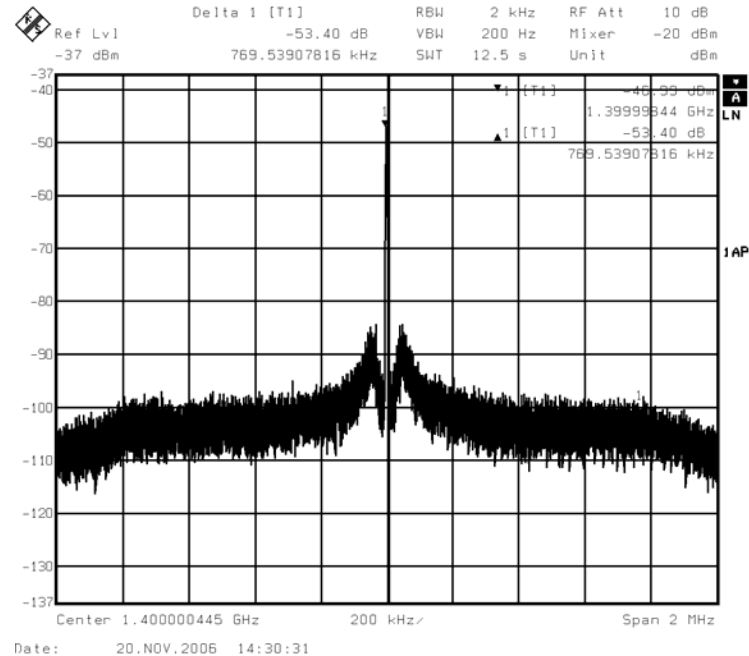
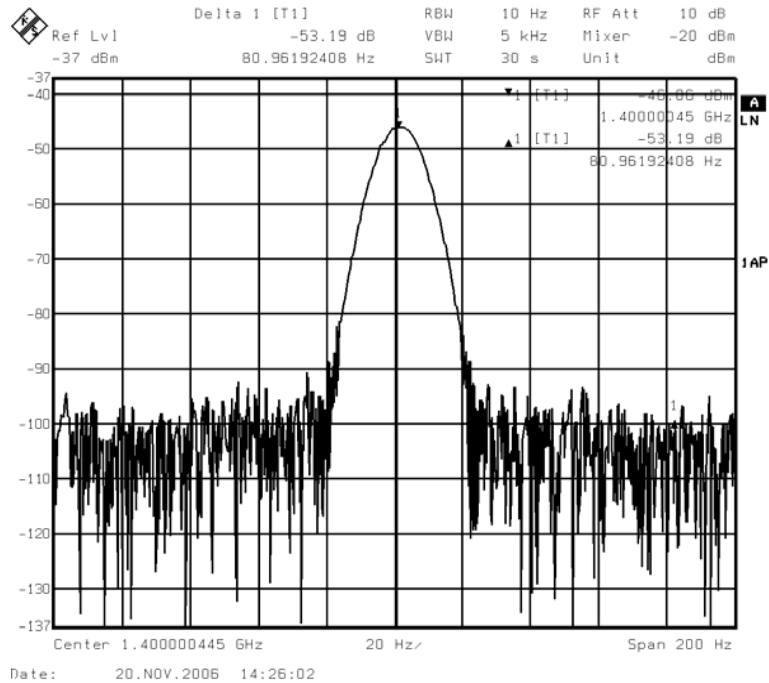
Downconversion measurement from RF_AMP input to PGA Output



1 LSB
 $\Sigma\Delta$ Offset = 2^{16}
 CLCK=24.778761 MHz
 Fine tuning 1LSB, step=189 Hz
 fLO1=1400 MHz, FLO2=200MHz
 MPLL1=7, MPLL2=8



SIGMA-DELTA L2 Spurs Both PLLS (2)

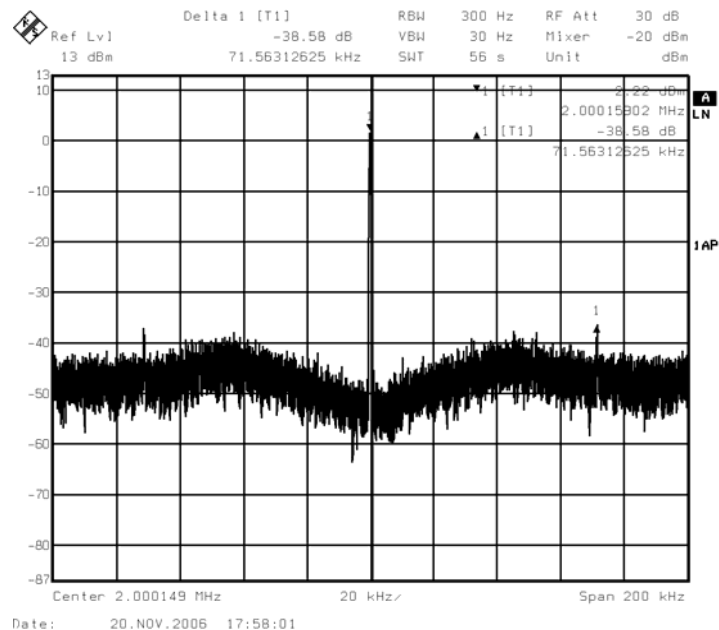
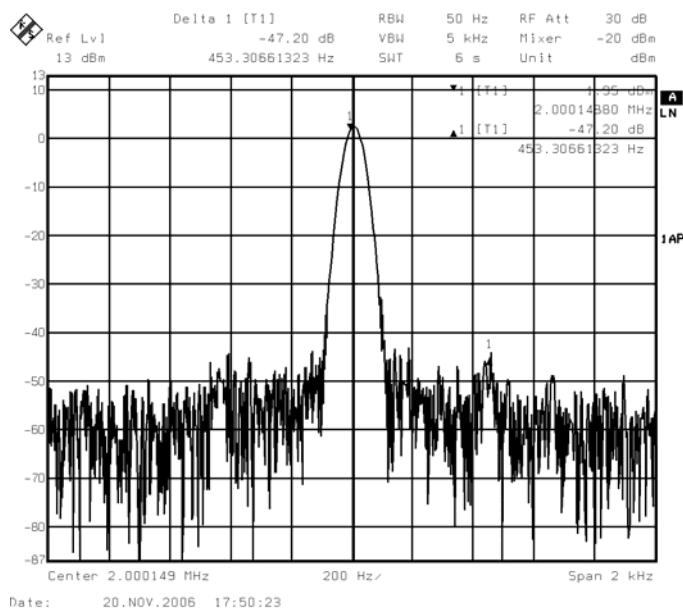


3 LSB
 $\Sigma\Delta$ Offset = 2^{16}
 CLCK=24.778761 MHz
 Fine tuning 3LSB, step=189Hz
 fLO1=1400 MHz, FLO2=200MHz
 MPLL1=7, MPLL2=8



SIGMA-DELTA Spurs L2 (PLL2 alone)

Downconversion measurement from RF_AMP input to PGA Output



4 LSB

$$\Sigma\Delta \text{ Offset} = 2^{16} + 2^{13} + 2^{10} + 2^7 + 2^4 + 2$$

CLCK=24.778761 MHz

Fine tuning 4LSB, step=23.7Hz

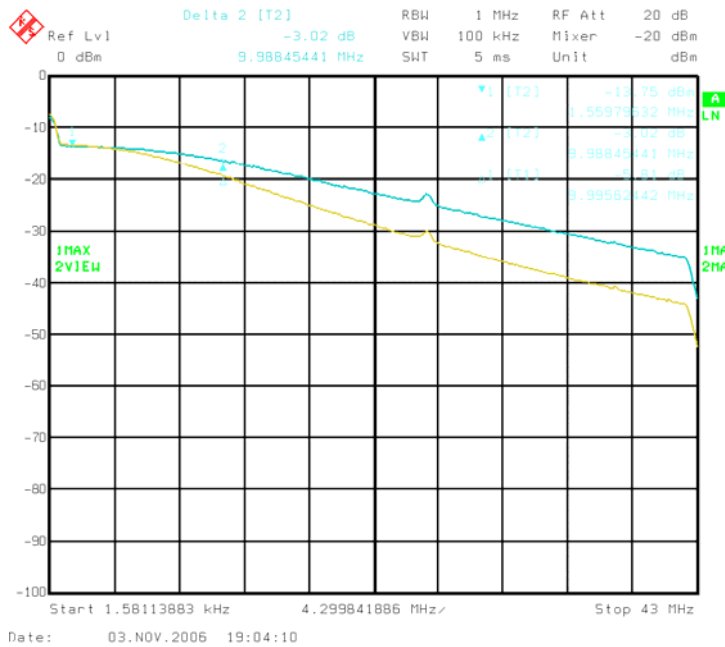
fLO1=1400 MHz, fLO2=200MHz

MPLL1=7, MPLL2=8

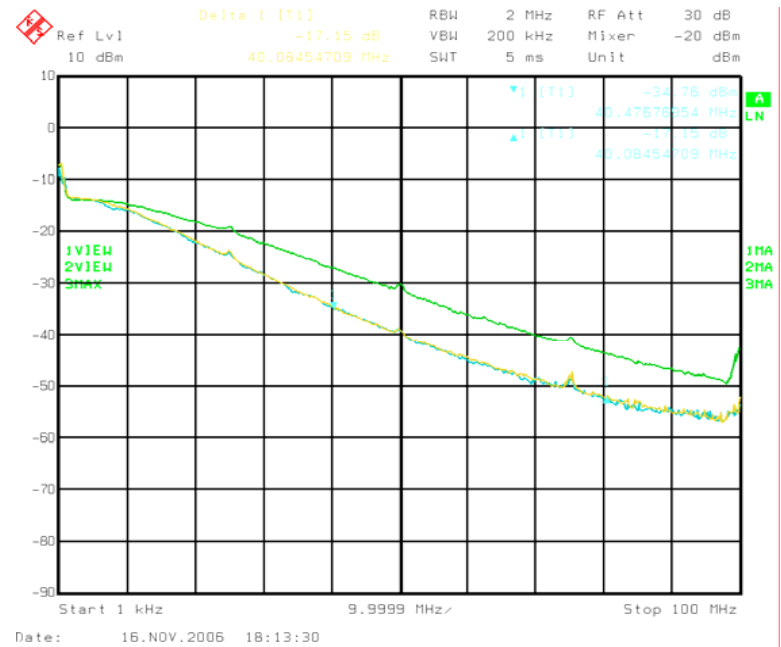


Lowpass Filters

Measured using test buffers



LPF-BW (L1) with tun=min
 (Y-trace=full BW; B-trace=1/2 BW)



LPF (L1) Attenuation
 LPF-BW: Y-trace=MIN tun; B-trace=Default tun; G-trace =
 Max tun



Channel Isolation

Settings:

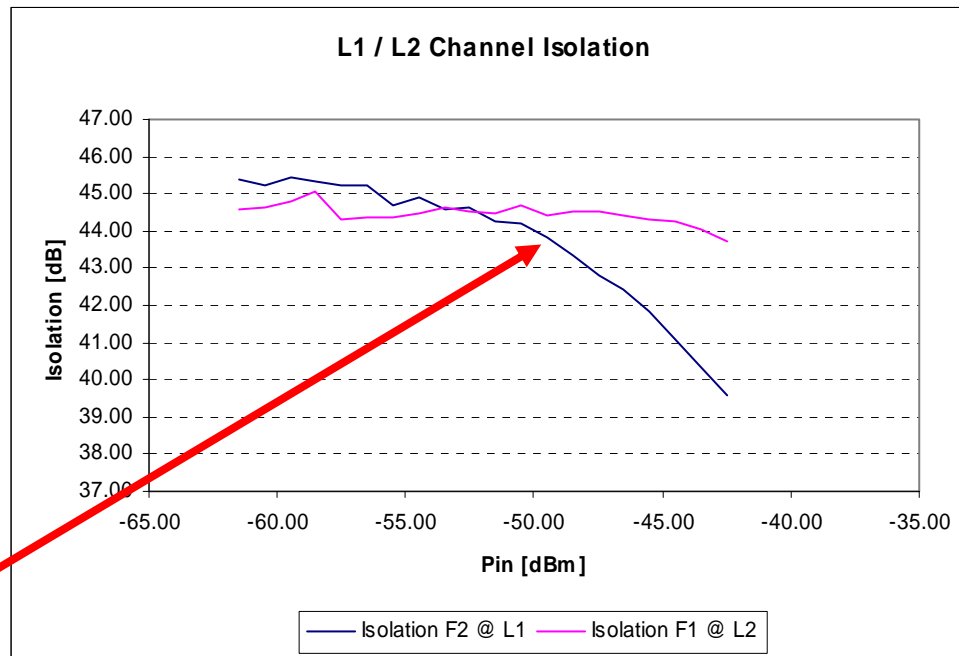
RF-Input Signal:

- F1=1.577GHz
- F2=1.202GHz

Input Chain:

- L1: MIX_IN_L1 (Balun Input - S5)
- L2: MIX_IN_L2 (Balun Input - S6)

PGA Gain:12dB





I Q Mismatch

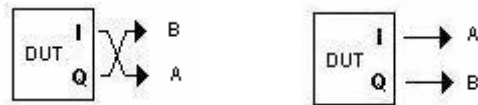
Setup:

RF-Input Signal:

- F1=1.577GHz
- F2=1.202GHz

Test Procedure:

In order to cancel the error in the path of the differential outputs (lines length, differential to single ended buffers...) the channels had been crossed in the following way:

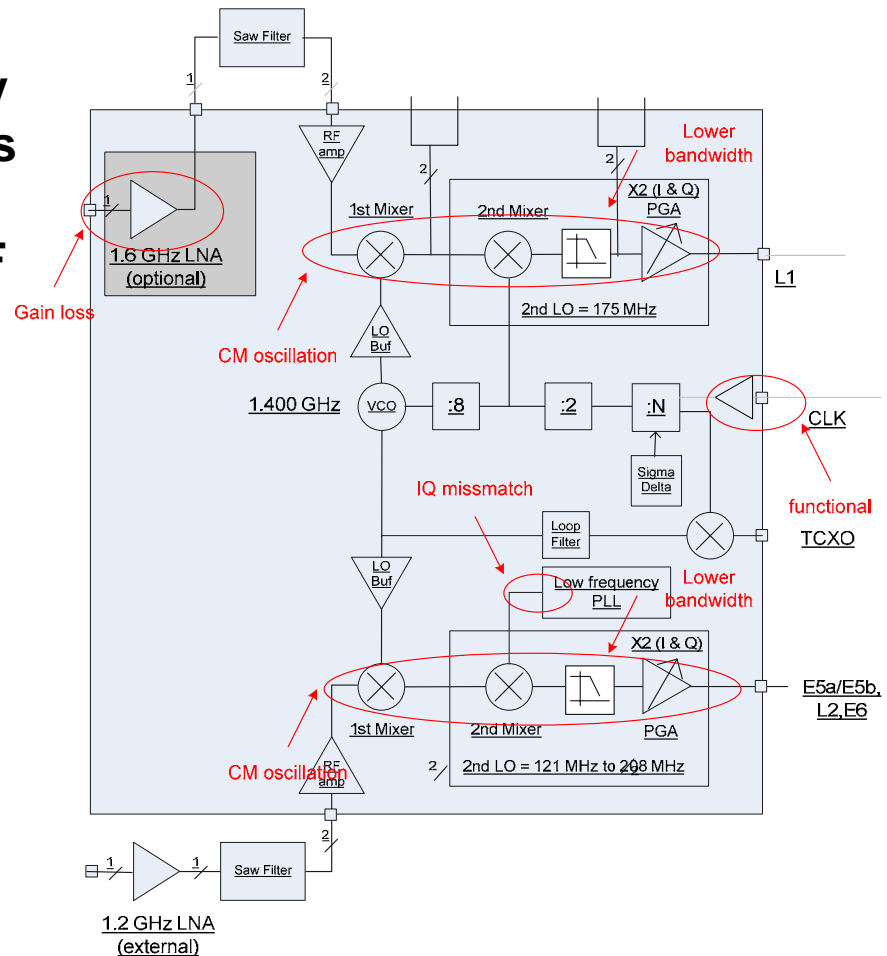


	Phase [deg]			Amplitude [dB]		
	I->A /Q->B	I->B /Q->A	Mismatch	I->A /Q->B	I->B /Q->A	Mismatch
L1	92.4	87.4	2.5	0.174	-0.105	0.14
L2	83.01	96.6	6.79	-0.68	0.9	0.79



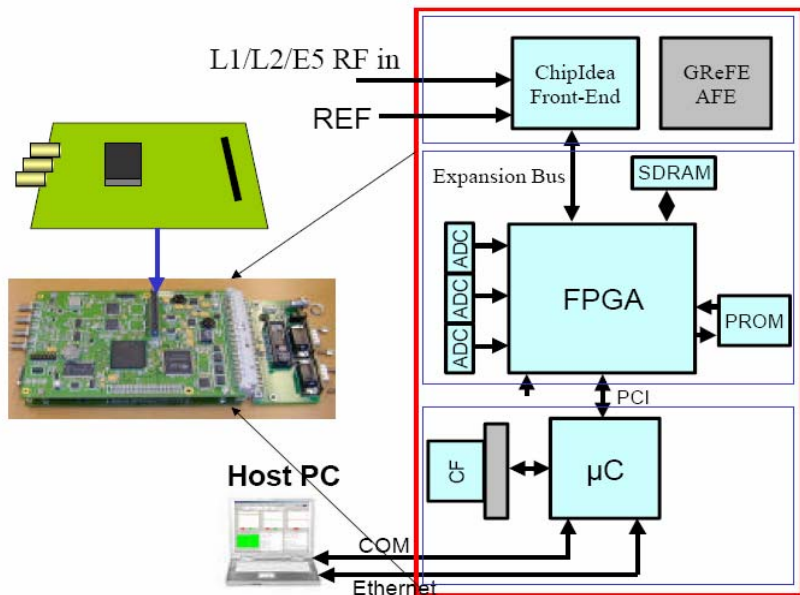
Future Work - Issues and Solutions

- Clock squarer functionality
- Common mode oscillations
- L2 IQ mismatch
- Lower LNA gain, higher NF
- Lower bandwidth





Future Work- Receiver Tests



- Feedback to our datasheet and feasibility study.
- Functional Test
- Logging Waveform (offline analysis)
- Interference Tests
- Detailed Navigation Performance Analysis

Figure 1-2: GPS/Galileo RX with Chip-Idea front-end



Future Work - Radiation Tests

Defined typical and worst cases radiation environment to be used as a baseline for the chip testing:

Scenario 1 (“typical”):

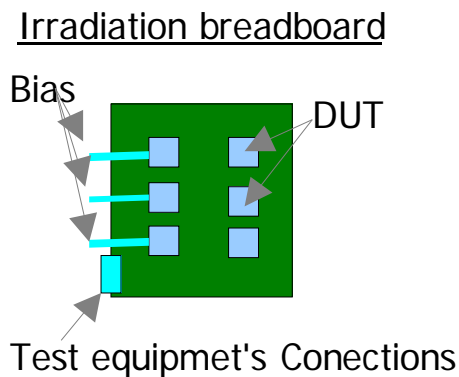
- LEO Polar orbit, with 900 Km altitude;
- “Quiet” Magnetic Weather Conditions (no magnetospheric storms);
- Solar Quiet (“no flare”) conditions (absence of solar energetic particle events);
- Solar Minimum cycle (cosmic ray maximum);

Scenario 2 (“worst case”):

- HEO orbit, with 20 000 Km altitude and 55° inclination (GPS constellation);
- “Stormy” Magnetic Weather Conditions;
- Solar-Energetic Particle (“flare”) conditions (worst-day);



- Objectives: Radiation assessment of the chip (TID)
- ESA ESTEC Co-60 facility
- Environment scenarios and radiation level of interest:
 - LEO – 40 kRads
 - MEO – 300 kRads (600kRads)
- Samples to be irradiated - 6
 - 3 biased
 - 3 not biased



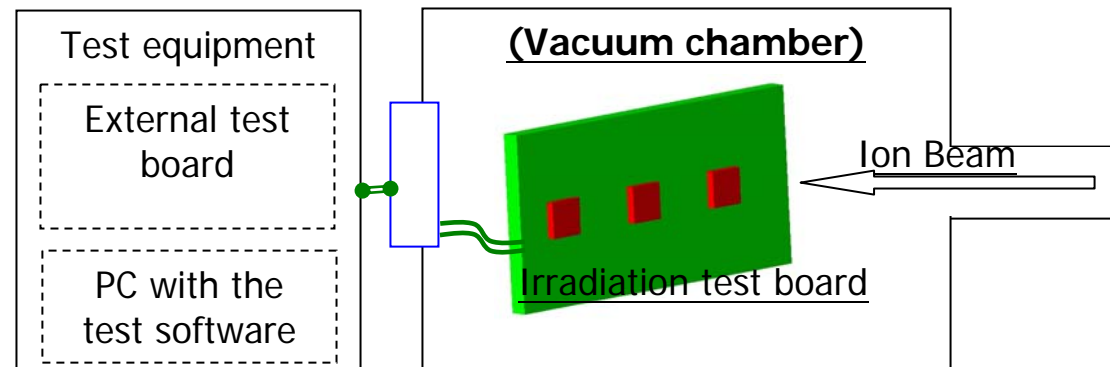
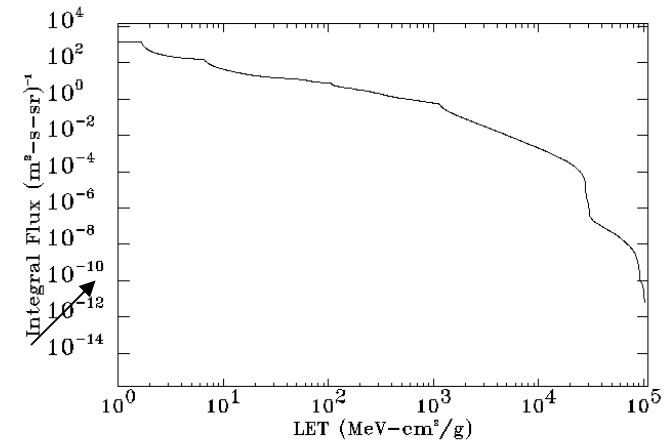
• Proposed Radiation Steps

Radiation level	Total dose (kRad)
M	3
D	10
E	20
F	40
R	100
A	300

- Radiation exposure rate 3.6 kRads/hr
- Other procedures after irradiation:
 - Annealing at room temperature
 - Accelerated aging



- Objectives: Radiation assessment of the chip (SEE)
- Facilities:
 - Heavy-ion Irradiation Facility (HIF)
 - RADIATION Effects Facility (RADEF)
- Environment & experimental testing parameters
 - Environment - CREME96 model
(ex: LET spectrum for polar quiet; polar orbit,..)
 - Ion cocktail selection in order to simulate the environment;
(other parameters: Fluence and flux)
- Experimental setup
 - objective: Characterization of the different SEE





Conclusions and directions

- First silicon run finished with very promising results:
 - Architecture validated
 - Performance of most IP blocks validated
- Second silicon run will include ...
 - performance tuning and...
 - functional improvements for receiver integration.
- High-end receiver performance tests
- Radiation tests
- High probability of productization complete in 2H2007